REVISIONS LTR DESCRIPTION DATE (YR-MO-DA) APPROVED Α Add case outline Y. Rewrite entire document. 93-06-11 K. A. Cottongim REV SHEET REV SHEET **REV STATUS** Α A REV A OF SHEETS 3 SHEET 10 14 PREPARED BY PMIC N/A Steve Duncan DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 STANDARDIZED CHECKED BY MILITARY Robert M. Heber DRAWING MICROCIRCUIT, LINEAR, RESOLVER OR APPROVED BY SYNCHRO-TO-DIGITAL CONVERTER, HYBRID William K. Heckman THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DRAWING APPROVAL DATE DEPARTMENT OF DEFENSE 90-10-10 SIZE CAGE CODE 5962-90554 AMSC N/A A 67268 REVISION LEVEL SHEET 1 15

DESC FORM 193

JUL 91

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

3

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1. SCOPE

- 1.1 <u>Scope</u>. This drawing describes device requirements for class H hybrid microcircuits to be processed in accordance with MIL-H-38534.
 - 1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:



1.2.1 <u>Device type(s)</u>. The device type(s) shall identify the circuit function as follows:

Device type	Generic number	Circuit function	Accuracy (±1.0 LSB)
01	HSDC-8915A	400 Hz, voltage follower buffer input	±2.6 arc minutes
01	XDC14507-628	400 Hz, voltage follower buffer input	±2.6 arc minutes
02	HSDC-8915	400 Hz, voltage follower buffer input	±4.0 arc minutes
02	XDC14507-627	400 Hz, voltage follower buffer input	±4.0 arc minutes

1.2.2 <u>Case outline(s)</u>. The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	Package style
X	See figure 1	36	Dual-in-line
Y	See figure 1	36	Dual-in-line

1.2.3 <u>Lead finish</u>. The lead finish shall be as specified in MIL-H-38534. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

1.3 Absolute maximum ratings. 1/

Supply voltage (V _S)	+18 V dc
Logic input voltage (V_L)	+15 V dc
Reference input	130 V rms
Digital inputs	-0.3 V dc to $V_{ m L}$
Power dissipation (PD)	270 mW <u>2</u> /
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	+300°C
Thermal resistance, junction-to-case (θ_{JC})	8.0°C/W
Thermal resistance, junction-to-ambient (θ_{JA})	28°C/W
Junction temperature (T ₁)	+150°C
•	

1.4 Recommended operating conditions.

Supply voltage range (V _S)	+11 V dc to +16.5 V dc
Logic input voltage (V_L)	+4.5 V dc to +15 V supply
Case operating temperature range $(T_{\mathbb{C}})$	-55°C to +125°C

²/ Power dissipation applies up to $T_C = +125$ °C.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-90554
DAYTON, OHIO 45444		REVISION LEVEL A	SHEET 2

DESC FORM 193A JUL 91

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^{1/} Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

2. APPLICABLE DOCUMENTS

2.1 <u>Government specification and standards</u>. Unless otherwise specified, the following specification and standards of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

7

MILITARY

MIL-H-38534 - Hybrid Microcircuits, General Specification for.

STANDARDS

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

MIL-STD-1835 - Microcircuit Case Outlines.

(Copies of the specification and standards required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

- 3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-H-38534 and as specified herein.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-H-38534 and herein.
 - 3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein and on figure 1.
 - 3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.
 - 3.2.3 Block diagram(s). The block diagram(s) shall be as specified on figure 3.
 - 3.2.4 <u>Digital angle output(s)</u>. The digital angle output(s) shall be as specified on figure 4.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.
- 3.5 <u>Marking</u>. Marking shall be in accordance with MIL-H-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML-38534 (see 6.6 herein).
- 3.6 <u>Manufacturer eligibility</u>. In addition to the general requirements of MIL-H-38534, the manufacturer of the part described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DESC-EC) upon request.
- 3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in QML-38534 (see 6.6 herein). The certificate of compliance submitted to DESC-EC prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-H-38534 and the requirements herein.
- 3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-H-38534 shall be provided with each lot of microcircuits delivered to this drawing.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-90554
DAYTON, OHIO 45444		REVISION LEVEL A	SHEET 3

DESC FORM 193A

JUL 91

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	Symbol	Conditions <u>1</u> / -55°C ≤ T _C ≤ +125°C	Group A subgroups	 Device type	 Limits		Unit
		-55°C ≤ T _C ≤ +125°C unless otherwise specified	specified specified		Min Max		
Resolution control		14 bits fail/pass	7,8	ALL			
Output accuracy		Measured at angles 0, 15, 30, 45, 60, 75, 90, 105, 120, 135, 150, 165, 180, 225, 270, and 315 degrees	7,8	ALL		2/	
Reference input							
Input voltage range	VIN		4,5,6	ALL	4.0	130	V rms
Carrier frequency			4,5,6	ALL	360	1000	Hz
Input impedence 3/	ZINREF		4,5,6	ALL	250		kΩ
		Differential			500		
Common mode voltage range <u>3</u> /	V _{CMREF}		4,5,6	ALL -210 +210		+210	V(pk)
Signal input				· · · · · · · · · · · · · · · · · · ·		. •	<u> </u>
Input impedence <u>3</u> /	z _{IN} .	 Voltage follower <u>4</u> /	4,5,6	ALL	10		MΩ
Sine/Cosine voltage range	V _{IN} L-L	 Line-to-line	4,5,6	ALL	0.9	1.1	V rms
Digital outputs (bits 1	through 1	4 and converter busy)	<u> </u>	I		. 	
Drive capability	v _{oL}	 Logic O, 1 TTL load at -1.6 mA	1,2,3	ALL		0.4	V dc
	V _{OH}	Logic 1, 10 TTL loads at 0.4 mA	1,2,3	All	2.8		V dc
	IX	 High impedence load	1,2,3	All	-1.0	-10	μΑ
	CB	 Positive pulse	9,10,11	ALL	0.5	2.0	μs

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TABLE I. <u>Electrical performance characteristics</u> - Continued. Conditions $\frac{1}{2}$ /
-55°C \leq T_C \leq +125°C
unless otherwise specified Test Symbol Group A Device Limits subgroups type Min Max Analog output AC error For ±1.0 LSB change, near 12.8 19.2 4,5,6 ALL е null to ground DC velocity voltage 0 At 2.1 rps 4,5,6 ALL 0.8 1.2

Unit

mV rms/LSB

V dc

V dc

V dc

V dc

8.0-

5.70

-5.70

Digital inputs (INH, $\overline{\text{EN 1-6}}$, $\overline{\text{EN 7-14}}$ an digital bits 1 through 14 while operating in CT mode

Full scale max., positive

Full scale max., negative

Per + lsb of error

direction

direction

Voltage inputs	v _{IL}	Logic 0, V _L = 5.0 V dc	1,2,3	ALL		1.5	V dc
	VIH	Logic 1, V _L = 5.0 V dc	1,2,3	ALL	3.5		V dc
Loading	ILOAD	 (internal pull-up)	1,2,3	All	-1.0	-10	μA
Inhibit	INH		7,8 <u>6</u> /	All			
Enable bits 1 to 6	EM		7,8 <u>7</u> /	ALL			
Enable bits 7 to 14	EL		7,8 <u>7</u> /	ALL			
Set	S		7,8 8/	ALL			

4,5,6

4,5,6

4,5,6

ALL

ALL

ALL

-1.2

3.72

-3.73

See footnotes at end of table.

Filtered dc error

Velocity 5/

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5962-90554
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5

DESC FORM 193A JUL 91

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TABLE I. Electrical performance characteristics - Continued. Unit Test Symbol Conditions $\frac{1}{-55^{\circ}c} \le \tau_{C} \le +125^{\circ}c$ unless otherwise specified Group A Device Limits subgroups type Min Max Power supplies Supply current Is Logic 0, $V_S = 16.5 \text{ V dc}$ 1,2,3 ALL 25 mA Logic supply current \mathbf{I}_{L} $V_L = 5.0 \text{ V dc}$ 1,2,3 ALL 1.0 mА

 $\underline{1}$ / V_S = +11 V dc to +16.5 v dc, V_L = +4.5 V dc to +15 V dc supply.

 $rac{4}{2}$ / The Sine/Cosine resolver signal is referenced to the converter internal dc reference ($extsf{V}_{ extsf{REF}}$).

5/ Test is performed at full speed of 10 rps.

Test should verify logic O enables, logic 1 high impedance.

8/ Test should verify logic 0 for use in CT mode.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-90554
DAYTON, OHIO 45444		REVISION LEVEL A	SHEET 6

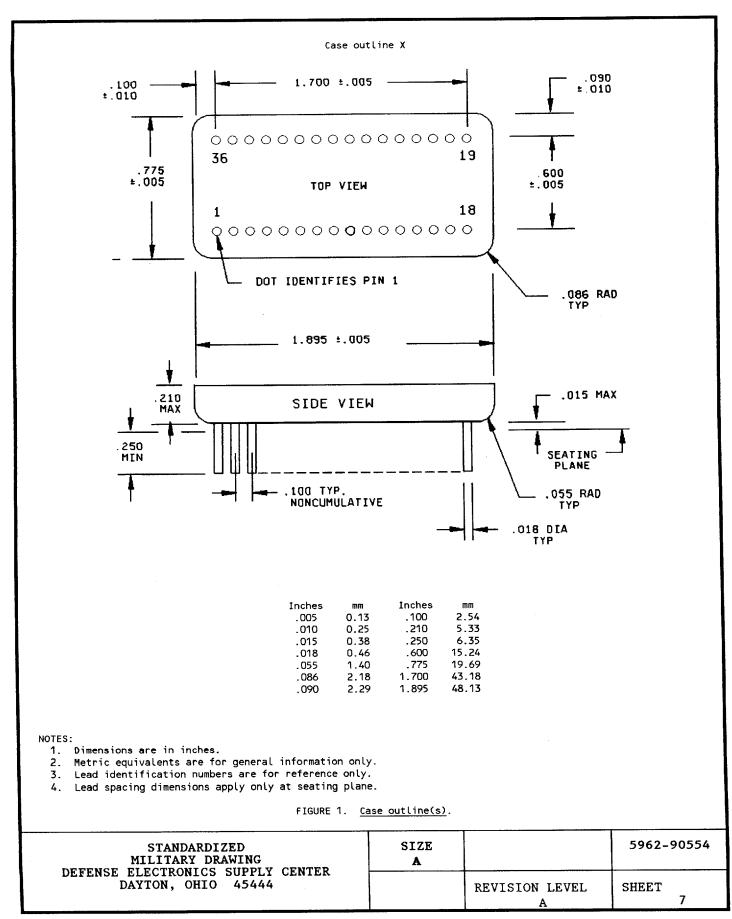
DESC FORM 193A JUL 91

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^{2/} Output accuracy for device type 01 is ±2.6 arc minutes ±1.0 LSB and output accuracy for device type 02 is ±4.0 arc minutes ±1.0 LSB.

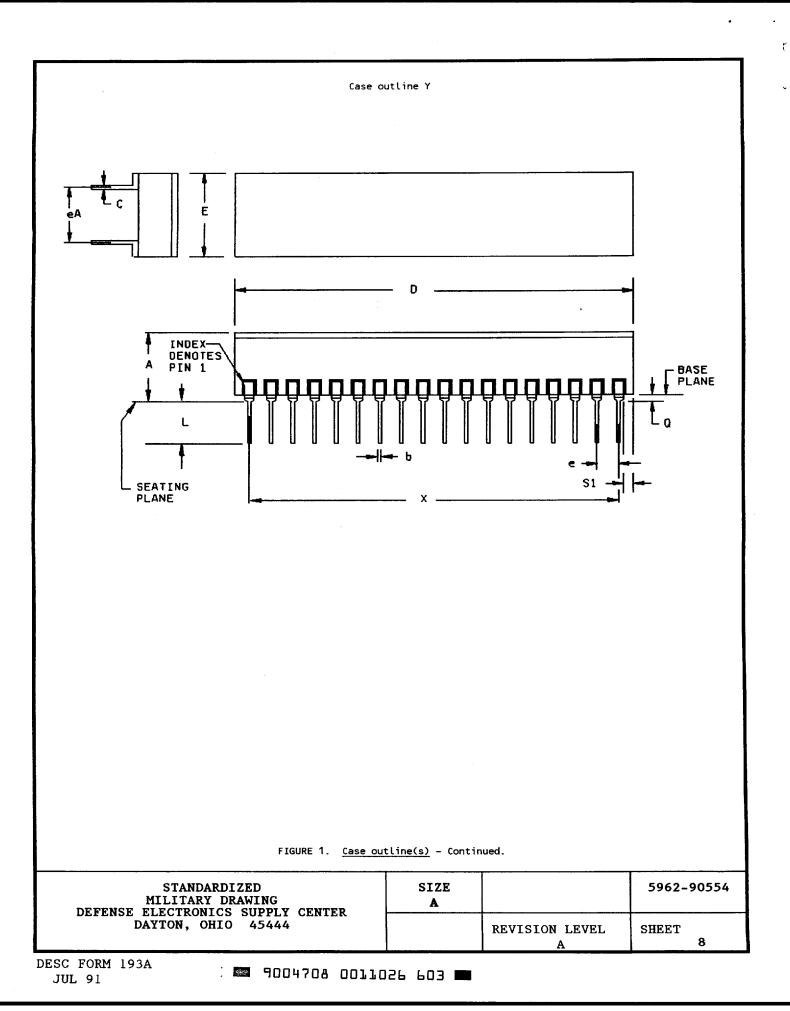
^{3/} Parameter shall be tested as part of device initial characterization and after design and process changes. Parameter shall be guaranteed to the limits specified in table I for all lots not specifically tested.

 $[\]overline{\underline{\delta}}/$ Test should verify no digital angles change while INH is logic 0 and analog input is rotating.



JUL 91

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Symbol	Millimeters		Inc	hes	
	Min	Max	Min	Max	
Α		5.33		0.210	
b	0.41	0.51	0.016	0.020	
С	0.41	0.51	0.016	0.020	
D		48.26		1.900	
E		20.32		0.800	
e	2.5	2.54 BSC		O BSC	
eA	15.11	15.37	0.595	0.605	
L	6.10	6.60	0.240	0.260	
Q		0.72		0.030	
\$1	2.18	2.44	0.086	0.096	
Х		18 BSC	1.70	O BSC	

NOTES:

 The U.S. preferred system of measurement is the metric SI. This item was designed using inch-pound units of measurement. In case of problems involving conflicts between the metric and inch-pound units, the inch-pound units shall rule.

FIGURE 1. <u>Case outline(s)</u> - Continued.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-90554
DAYTON, OHIO 45444		REVISION LEVEL	SHEET 9

DESC FORM 193A JUL 91

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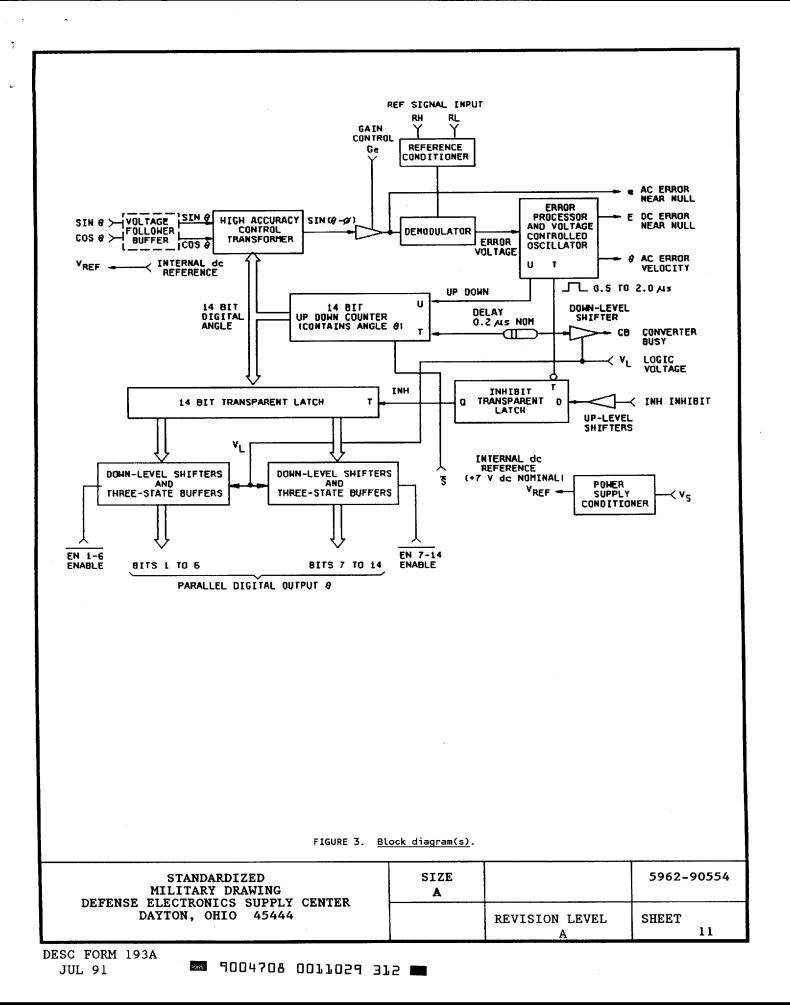
Device types	01 and 02
Case outlines	X and Y
Terminal number	Terminal symbol
1 2 3 4 5 6 7 8 8 9 10 11 12 13 14 15 16 17 18	NC COSINE SINE NC BIT 1 MSB BIT 2 BIT 3 BIT 4 BIT 5 BIT 6 BIT 7 BIT 8 BIT 9 BIT 10 BIT 11 BIT 12 BIT 12 BIT 13 BIT 14

Device types	01 and 02		
Case outlines	X and Y		
Terminal number	Terminal symbol		
19 20 21 22 23 24 25 26 27 28 29 30 31	RH (reference high) RL (reference low) NC E (filtered dc error out) O (analog velocity out) CB (converter busy) EN 7-14 (enable, bits 7-14) EN 1-6 (enable, bits 1-6) e (AC error out) VL (logic voltage input) GND S Ge (gain control)		
33 34 35 36	V _S (power supply in) INH (inhibit) V _{REF} (internal dc reference) BC (buffered cosine) BS (buffered sine)		

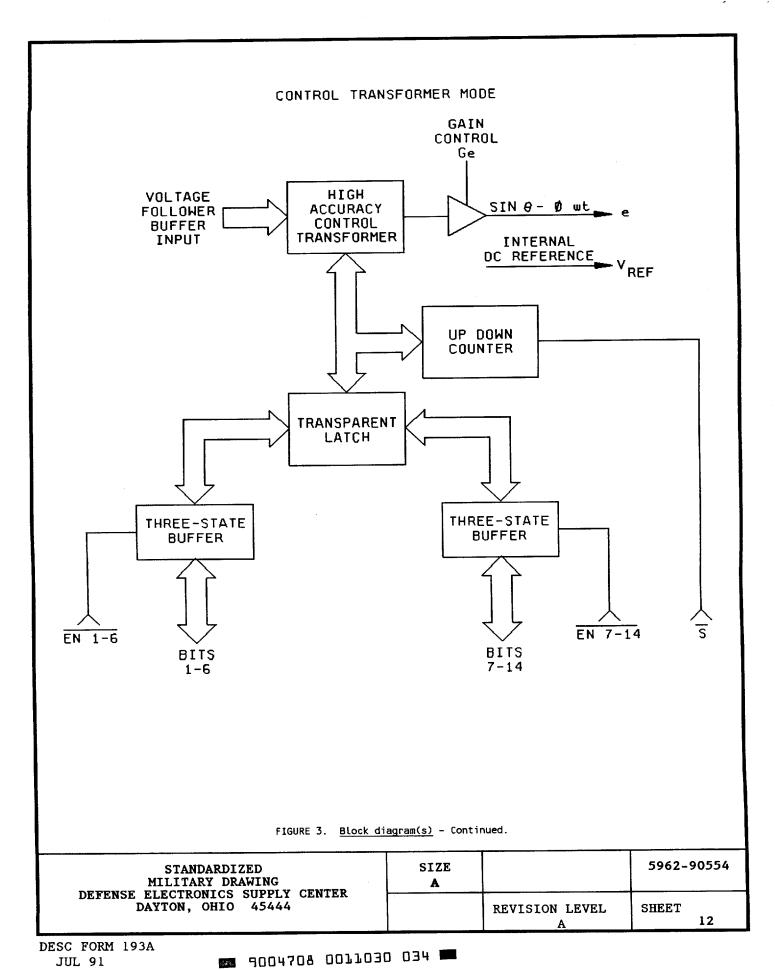
FIGURE 2. <u>Terminal connections</u>.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-90554
		REVISION LEVEL A	SHEET 10

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Bit	Degree per bit	Minute per bit
1 MSB	180	10,800
2	90	5,400
3	45	2,700
4	22.5	1,350
5	11.25	675
6	5.625	387.5
7	2.813	168.75
8	1.405	84.38
9	0.7031	42.19
10	0.3516	21.09
11	0.1758	10.55
12	0.0879	5.27
13	0.0439	2.64
14 LSB	0.0220	1.32

FIGURE 4. Digital angle output(s).

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-90554
		REVISION LEVEL A	SHEET

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TABLE II. Electrical test requirements.

MIL-H-38534 test requirements	Subgroups (in accordance with MIL-H-38534, group A test table)
Interim electrical parameters	1,4,7,9
Final electrical test parameters	1*,2,3,4,5,6,7,8,9, 10,11
Group A test requirements	1,2,3,4,5,6,7,8,9,10
Group C end-point electrical parameters	1,2,3,4,5,6,7,8,9,10,

^{*} PDA applies to subgroup 1.

- 4. QUALITY ASSURANCE PROVISIONS
- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-H-38534.
- 4.2 <u>Screening</u>. Screening shall be in accordance with MIL-H-38534. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DESC-EC or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with MIL-H-38534 and as specified herein.
- 4.3.1 <u>Group A inspection</u>. Group A inspection shall be in accordance with MIL-H-38534 and tests shall be as specified in table II herein.
 - 4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-H-38534.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-90554
		REVISION LEVEL A	SHEET 14

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- 4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DESC-EC or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) TA as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
- 4.3.4 Group D inspection. Group D inspection shall be in accordance with MIL-H-38534.
- PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-H-38534.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-EC, telephone (513) 296-6047.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-EC, Dayton, Ohio 45444, or telephone (513) 296-5373.
- 6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in QML-38534. Additional sources will be added to QML-38534 as they become available. The vendors listed in QML-38534 have agreed to this drawing and a certificate of compliance (see 3.7 herein) has been submitted to and accepted by DESC-EC.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-90554
		REVISION LEVEL A	SHEET 15

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